UNIVERSITÄT BERN

MIC training: Super resolution microscopy

Date:	March 1-2, 2021
Time:	9 am – 5 pm
Location:	Online in Zoom, using this meeting link.
Trainers:	Dr. Christine Strasser (Zeiss, Feldbach, CH), Dr. Marko Lampe (EMBL Heidelberg, DE), Dr. Jana Doehner (University of Zurich, CH), Dr. Yury Belyaev (University of Bern, CH)
Organizer:	Dr. Y. Belyaev, University of Bern. MIC of the University of Bern (www.mic.unibe.ch). Supported by the PhD specialization Cutting Edge Microscopy.
Max number of participants:	minimum 5, maximum 25
Registration:	until February 25, 2021, please use this link.
Target audience:	PhD students, postdocs, and everyone who needs super resolution microscopy in their research. Participants of Cutting Edge Microscopy specialization program are particularly invited.
Credits:	Certificate of attendance. On request, PhD students of the Cutting Edge Microscopy program can obtain 1.0 ECTS for this course with presenting the learning outcome in the context of his/her project at a separate meeting.
Background:	STED from Leica and Airyscan from Zeiss allow for resolution enhancement, both microscopy methods are available at MIC.
Content:	Overview of super resolution microscopy methods, sample preparation. Basics of STED and Airyscan techniques.
Learning outcome:	Participants will learn how to prepare samples and perform STED and Airyscan imaging.
Schedule:	See next page.

Super resolution microscopy

Time	Day 1 (01.03.2021)	Day 2 (02.03.2021)
9:00-12:00	**Lectures, Zoom** Nanoscopy M. Lampe, EMBL STED M. Lampe, EMBL Airyscan C. Strasser, Zeiss	**Lectures, Zoom** SR sample preparation J. Doehner, UZH **Hands-on, Zoom** Deconvolution Y. Belyaev, MIC, M. Lampe, EMBL
12:00-13:30	**Lunch**	**Lunch**
13:30-17:00	**Hands-on, Zoom** Airyscan basics C. Strasser, Zeiss STED basics M. Lampe, EMBL	**Hands-on, Zoom** Airyscan advanced C. Strasser, Zeiss STED advanced M. Lampe, EMBL